

**7th EUropean Failure Analysis
NETwork EUFANET workshop**

**ESD, ESDFOS and EOS from a
Failure Analysis point of view**

October 10, EUFANET Workshop at ESREF 2007

EUFANET Status Update

- 250 Members, 18 countries
- EUFANET kick off (2001)
- Email Forum (2002)
- Web site (2003)
 - FA Database (2005)
 - Yellowpages (2006)
- EUFANET legal status (2005)
- EUFANET board Election (end 2006)
- ... **specifics 2 days workshop on FA hot topic**
(in conjunction with CCT, in Toulouse) ?

Board of Directors

- Christian BOIT (TUB Berlin University of Technology)
- Dioniz POGANY (Institute for Solid State Electronics, Vienna University of Technology)
- Eckhard LANGER (AMD Saxony)
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- Jerome TOUZEL (INFINEON)
- Peter JACOB (EMPA)
- Philippe PERDU (CNES)
- Yves OUSTEN (University Bordeaux 1 - IMS)

Workshop program

- 17h40** Welcome and EUFANET status update
Philippe Perdu, CNES and Felix Beaudoin, CREDENCE
- 17h50** Introduction to ESD challenges
Peter Jacob, EMPA
- 18h10** Electrical and physical signatures of EOS and ESD defects:
ANADEF workgroup report
Philippe Perdu, CNES
- 18h30** ESD characterization and failure reproduction
Horst Gieser, Fraunhofer Institute
- 18h50** The difficult art of locating an ESD failure and identifying its
root cause: from physical signature to latent defect
Marise Bafleur, LAAS
- 19h10** ESD concerns in sawing wafers with or without CO2 bubbling
Reinhold Gaertner, Infineon
- 19h30** Closing remarks